

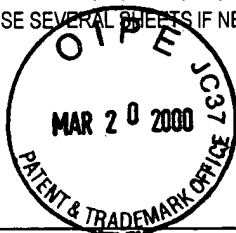
FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

## INFORMATION DISCLOSURE STATEMENT

BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)



ATTY. DOCKET NO.

FILLF1.0001CP1

APPLICATION NO.

09/460,630

APPLICANT

Dierickx

FILING DATE

DECEMBER 14, 1999

GROUP


2811

## U.S. PATENT DOCUMENTS

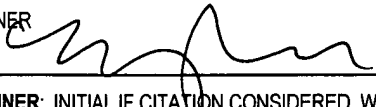
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
EL	4,473,836	9/25/84	Chamberlain			
EL	4,565,756	1/21/86	Needs et al.			
EL	4,580,103	4/1/86	Tompsett			
EL	4,647,975	3/3/87	Alston et al.			
EL	5,146,074	9/8/92	Kawahara et al.			
EL	5,153,420	10/6/92	Hack et al.			
EL	5,164,832	11/17/92	Halvis et al.			
EL	5,258,845	11/2/93	Kyuma et al.			
EL	5,296,696	3/22/94	Uno			
EL	5,321,528	6/14/94	Nakamura			
EL	5,335,008	8/2/94	Hamasaki			
EL	5,608,204	3/4/97	Hofflinger et al.			
EL	5,614,744	3/25/97	Merrill			
EL	5,841,126	11/24/98	Fossum			
EL	5,898,196	4/27/99	Hook et al.			
EL	5,101,253	3/31/92	Mizutani et al.			
EL	5,903,021	5/11/99	Lee et al.			
EL	5,625,210	4/29/97	Leet et al.			
EL	5,904,493	5/18/99	Lee et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
EL	548 987	6/30/93	Europe				
EL	657 863	6/14/95	Europe				
EL	739 039	10/23/96	Europe				
EL	93/19489	9/30/93	PCT				
EL	2324651	28/10/98	Great Britain				

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		APPLICANT Dierickx	
		FILING DATE DECEMBER 14, 1999	GROUP 2811

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
EL	Aoki et al., "A Collinear 3-Chip Image Sensor", <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 102-103.
EL	Hori et al., "A 490 x 404 Element Imager for a Single-Chip Color Camera", <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 96-97.
EL	Nagakawa et al., "A 580 x 500-Element CCD Imager with a Shallow Flat P Well", <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp.98-99.
EL	Mahowald, M.A., "Silicon Retina with Adaptive Photoreceptors", <u>SPIE</u> , Vol. 1473, 1991, pp. 52-58.
EL	Mann, J. "Implementing Early Visual Processing In Analog VLSI: Light Adaptation", <u>SPIE</u> , Vol 1473, 1991, pp. 128-136.
EL	Ono et al., "Analysis of Smear Noise In Interline-CCD Image Sensor with Gate-Free Isolation Structure", Abstract of the 1991 Int'l Conference on Solid State Devices and Materials, Yokohama, 1991, pp. 68-70.
EL	Yadid-Pecht et al., "A Random Access Photodiode Array for Intelligent Image Capture", <u>IEEE Transactions on Electron Devices</u> , Vol. 38, No. 8 August 1991.
EL	Ricquier et al., "Pixel Structure with Logarithmic Response for Intelligent and Flexible Imager Architectures", <u>Microelectronic Engineering</u> , 19 (1992), pp. 631-634
EL	Sevenhans, et al., "A 400mm Long Linear X-Ray Sensitive Image Sensor", <u>IEEE International Solid-State Circuits Conference</u> , 1987, pp. 108-109.
EL	Anderson, S. et al., "A Single Chip Sensor & Image Processor or Fingerprint Verification", <u>IEEE 1991 Custom Integrated Circuits Conference</u> , May 12-15, 1991, pp. 12.1.1-12.1.4.
EL	Dierickx, Bart, "XYW Detector: A Smart Two-Dimensional Particle Sensor", <u>Nuclear Instruments and Methods in Physics Research A275</u> , North-Holland Physics Publishing Division, 1989, pp. 542-544.
EL	Klein, P., "Design and Performance of Semiconductor Detectors with Integrated Amplification and Charge Storage Capability", <u>Nuclear Instruments and Methods in Physics Research A305</u> , 1991, pp. 517-526.
EL	Aw, Chye Huat, et al., "A 128 x 128-Pixel Standard-CMOS Image Sensor with Electronic Shutter", <u>IEEE Journal of Solid State Circuits</u> , Vol.31, No. 12, December 1996, pp. 1922-1930.
EL	Martin, W.J. et al., "Dynamic Offset Null", <u>IBM Technical Disclosure Bulletin</u> , No. 23, No. 9, February 1981, pp. 4195-4196.

EXAMINER 	DATE CONSIDERED 5/10/01
<p><b>*EXAMINER:</b> INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.</p>	